NXP USA Inc. - MC9S08AW60MPUE Datasheet





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Details

Product Status	Active
Core Processor	S08
Core Size	8-Bit
Speed	40MHz
Connectivity	I ² C, SCI, SPI
Peripherals	LVD, POR, PWM, WDT
Number of I/O	54
Program Memory Size	60KB (60K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	2K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.5V
Data Converters	A/D 16x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mc9s08aw60mpue

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Part Number	Package Description	Original (gold wire) package document number	Current (copper wire) package document number
MC68HC908JW32	48 QFN	98ARH99048A	98ASA00466D
MC9S08AC16			
MC9S908AC60			
MC9S08AC128			
MC9S08AW60			
MC9S08GB60A			
MC9S08GT16A			
MC9S08JM16			
MC9S08JM60			
MC9S08LL16			
MC9S08QE128			
MC9S08QE32			
MC9S08RG60			
MCF51CN128			
MC9RS08LA8	48 QFN	98ARL10606D	98ASA00466D
MC9S08GT16A	32 QFN	98ARH99035A	98ASA00473D
MC9S908QE32	32 QFN	98ARE10566D	98ASA00473D
MC9S908QE8	32 QFN	98ASA00071D	98ASA00736D
MC9S08JS16	24 QFN	98ARL10608D	98ASA00734D
MC9S08QB8			
MC9S08QG8	24 QFN	98ARL10605D	98ASA00474D
MC9S08SH8	24 QFN	98ARE10714D	98ASA00474D
MC9RS08KB12	24 QFN	98ASA00087D	98ASA00602D
MC9S08QG8	16 QFN	98ARE10614D	98ASA00671D
MC9RS08KB12	8 DFN	98ARL10557D	98ASA00672D
MC9S08QG8	1		
MC9RS08KA2	6 DFN	98ARL10602D	98ASA00735D





4.4.5 Access Errors

An access error occurs whenever the command execution protocol is violated.

Any of the following specific actions will cause the access error flag (FACCERR) in FSTAT to be set. FACCERR must be cleared by writing a 1 to FACCERR in FSTAT before any command can be processed.

- Writing to a FLASH address before the internal FLASH clock frequency has been set by writing to the FCDIV register
- Writing to a FLASH address while FCBEF is not set (A new command cannot be started until the command buffer is empty.)
- Writing a second time to a FLASH address before launching the previous command (There is only one write to FLASH for every command.)
- Writing a second time to FCMD before launching the previous command (There is only one write to FCMD for every command.)
- Writing to any FLASH control register other than FCMD after writing to a FLASH address
- Writing any command code other than the five allowed codes (\$05, \$20, \$25, \$40, or \$41) to FCMD
- Accessing (read or write) any FLASH control register other than the write to FSTAT (to clear FCBEF and launch the command) after writing the command to FCMD.
- The MCU enters stop mode while a program or erase command is in progress (The command is aborted.)
- Writing the byte program, burst program, or page erase command code (\$20, \$25, or \$40) with a background debug command while the MCU is secured (The background debug controller can only do blank check and mass erase commands when the MCU is secure.)
- Writing 0 to FCBEF to cancel a partial command

4.4.6 FLASH Block Protection

The block protection feature prevents the protected region of FLASH from program or erase changes. Block protection is controlled through the FLASH Protection Register (FPROT). When enabled, block protection begins at any 512 byte boundary below the last address of FLASH, \$FFFF. (see Section 4.6.4, "FLASH Protection Register (FPROT and NVPROT)").

After exit from reset, FPROT is loaded with the contents of the NVPROT location which is in the nonvolatile register block of the FLASH memory. FPROT cannot be changed directly from application software so a runaway program cannot alter the block protection settings. Since NVPROT is within the last 512 bytes of FLASH, if any amount of memory is protected, NVPROT is itself protected and cannot be altered (intentionally or unintentionally) by the application software. FPROT can be written through background debug commands which allows a way to erase and reprogram a protected FLASH memory.

The block protection mechanism is illustrated below. The FPS bits are used as the upper bits of the last address of unprotected memory. This address is formed by concatenating FPS7:FPS1 with logic 1 bits as shown. For example, in order to protect the last 8192 bytes of memory (addresses \$E000 through \$FFFF), the FPS bits must be set to 1101 111 which results in the value \$DFFF as the last address of unprotected memory. In addition to programming the FPS bits to the appropriate value, FPDIS (bit 0 of NVPROT) must



Chapter 6 Parallel Input/Output

- Software-controlled slew rate output buffers
- Eight port A pins
- Eight port B pins shared with ADC1
- Seven port C pins shared with SCI2, IIC1, and MCLK
- Eight port D pins shared with ADC1, KBI1, and TPM1 and TPM2 external clock inputs
- Eight port E pins shared with SCI1, TPM1, and SPI1
- Eight port F pins shared with TPM1 and TPM2
- Seven port G pins shared with XTAL, EXTAL, and KBI1

6.3 Pin Descriptions

The MC9S08AW60 Series has a total of 54 parallel I/O pins in seven ports (PTA–PTG). Not all pins are bonded out in all packages. Consult the pin assignment in Chapter 2, "Pins and Connections," for available parallel I/O pins. All of these pins are available for general-purpose I/O when they are not used by other on-chip peripheral systems.

After reset, the shared peripheral functions are disabled so that the pins are controlled by the parallel I/O. All of the parallel I/O are configured as inputs (PTxDDn = 0). The pin control functions for each pin are configured as follows: slew rate control enabled (PTxSEn = 1), low drive strength selected (PTxDSn = 0), and internal pullups disabled (PTxPEn = 0).

The following paragraphs discuss each port and the software controls that determine each pin's use.

6.3.1 Port A

Figure 6-1. Port A Pin Names										
	MCU Pin:	PTA7	PTA6	PTA5	PTA4	PTA3	PTA2	PTA1	PTA0	
Port A		Bit 7	6	5	4	3	2	1	Bit 0	

Port A pins are general-purpose I/O pins. Parallel I/O function is controlled by the port A data (PTAD) and data direction (PTADD) registers which are located in page zero register space. The pin control registers, pullup enable (PTAPE), slew rate control (PTASE), and drive strength select (PTADS) are located in the high page registers. Refer to Section 6.4, "Parallel I/O Control" for more information about general-purpose I/O control and Section 6.5, "Pin Control" for more information about pin control.

6.3.2 Port B

Port B		Bit 7	6	5	4	3	2	1	Bit 0		
	MCU Pin:	PTB7/ AD1P7	PTB6/ AD1P6	PTB5/ AD1P5	PTB4/ AD1P4	PTB3/ AD1P3	PTB2/ AD1P2	PTB1/ AD1P1	PTB0/ AD1P0		

Figure 6-2. Port B Pin Names

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pullup enable (PTDPE), slew rate control (PTDSE), and drive strength select (PTDDS) are located in the high page registers. Refer to Section 6.4, "Parallel I/O Control" for more information about general-purpose I/O control and Section 6.5, "Pin Control" for more information about pin control.

Port D general-purpose I/O are shared with the ADC, KBI, and TPM1 and TPM2 external clock inputs. When any of these shared functions is enabled, the direction, input or output, is controlled by the shared function and not by the data direction register of the parallel I/O port. When a pin is shared with both the ADC and a digital peripheral function, the ADC has higher priority. For example, in the case that both the ADC and the KBI are configured to use PTD7 then the pin is controlled by the ADC module.

Refer to Chapter 10, "Timer/PWM (S08TPMV2)" for more information about using port D pins as TPM external clock inputs.

Refer to Chapter 14, "Analog-to-Digital Converter (S08ADC10V1)" for more information about using port D pins as analog inputs.

Refer to Chapter 9, "Keyboard Interrupt (S08KBIV1)" for more information about using port D pins as keyboard inputs.

6.3.5 Port E

Port E

	Bit 7	6	5	4	3	2	1	Bit 0
MCU Pin:	PTE7/	PTE6/	PTE5/	PTE4/	PTE3/	PTE2/	PTE1/	PTE0/
	SPSCK1	MOSI1	MISO1	SS1	TPM1CH1	TPM1CH0	RxD1	TxD1

Figure 6-5. Port E Pin Names

Port E pins are general-purpose I/O pins. Parallel I/O function is controlled by the port E data (PTED) and data direction (PTEDD) registers which are located in page zero register space. The pin control registers, pullup enable (PTEPE), slew rate control (PTESE), and drive strength select (PTEDS) are located in the high page registers. Refer to Section 6.4, "Parallel I/O Control" for more information about general-purpose I/O control and Section 6.5, "Pin Control" for more information about pin control.

Port E general-purpose I/O is shared with SCI1, SPI, and TPM1 timer channels. When any of these shared functions is enabled, the direction, input or output, is controlled by the shared function and not by the data direction register of the parallel I/O port. Also, for pins which are configured as outputs by the shared function, the output data is controlled by the shared function and not by the port data register.

Refer to Chapter 11, "Serial Communications Interface (S08SCIV2)" for more information about using port E pins as SCI pins.

Refer to Chapter 12, "Serial Peripheral Interface (S08SPIV3)" for more information about using port E pins as SPI pins.

Refer to Chapter 10, "Timer/PWM (S08TPMV2)" for more information about using port E pins as TPM channel pins.



Chapter 6 Parallel Input/Output

	7	6	5	4	3	2	1	0
R W	PTASE7	PTASE6	PTASE5	PTASE4	PTASE3	PTASE2	PTASE1	PTASE0
Reset	0	0	0	0	0	0	0	0

Figure 6-12. Output Slew Rate Control Enable for Port A (PTASE)

Table 6-5. PTASE Register Field Descriptions

Field	Description
7:0 PTASE[7:0]	 Output Slew Rate Control Enable for Port A Bits — Each of these control bits determine whether output slew rate control is enabled for the associated PTA pin. For port A pins that are configured as inputs, these bits have no effect. Output slew rate control disabled for port A bit n. Output slew rate control enabled for port A bit n.

_	7	6	5	4	3	2	1	0
R	PTADS7	PTADS6	PTADS5	PTADS4	PTADS3	PTADS2	PTADS1	PTADS0
W								
Reset	0	0	0	0	0	0	0	0

Figure 6-13. Output Drive Strength Selection for Port A (PTASE)

Table 6-6. PTASE Register Field Descriptions

Field	Description
7:0 PTADS[7:0]	 Output Drive Strength Selection for Port A Bits — Each of these control bits selects between low and high output drive for the associated PTA pin. 0 Low output drive enabled for port A bit n. 1 High output drive enabled for port A bit n.



Source	Onenstian	Description		c	Eff	ec CC	t R		ess de	ode	and	/cles ¹
Form	Operation	Description	v	н	I	N	z	с	Addr Mo	Opce	Oper	Bus Cy
BCLR n,opr8a	Clear Bit n in Memory	Mn ← 0	_	_	_	_	_	_	DIR (b0) DIR (b1) DIR (b2) DIR (b3) DIR (b4) DIR (b5) DIR (b6) DIR (b7)	11 13 15 17 19 1B 1D 1F	dd dd dd dd dd dd dd dd dd	5555555555
BCS rel	Branch if Carry Bit Set (Same as BLO)	Branch if $(C) = 1$	-	-	-	-	-	-	REL	25	rr	3
BEQ rel	Branch if Equal	Branch if (Z) = 1	-	-	-	-	-	-	REL	27	rr	3
BGE rel	Branch if Greater Than or Equal To (Signed Operands)	Branch if $(N \oplus V) = 0$	-	-	-	-	-	-	REL	90	rr	3
BGND	Enter Active Background if ENBDM = 1	Waits For and Processes BDM Commands Until GO, TRACE1, or TAGGO	-	-	-	-	-	-	INH	82		5+
BGT rel	Branch if Greater Than (Signed Operands)	Branch if (Z) (N \oplus V) = 0	-	-	-	-	-	-	REL	92	rr	3
BHCC rel	Branch if Half Carry Bit Clear	Branch if (H) = 0	-	-	-	-	-	-	REL	28	rr	3
BHCS rel	Branch if Half Carry Bit Set	Branch if (H) = 1	-	-	-	-	-	-	REL	29	rr	3
BHI <i>rel</i>	Branch if Higher	Branch if $(C) \mid (Z) = 0$	-	-	-	-	-	-	REL	22	rr	3
BHS rel	Branch if Higher or Same (Same as BCC)	Branch if $(C) = 0$	-	-	-	-	-	-	REL	24	rr	3
BIH rel	Branch if IRQ Pin High	Branch if IRQ pin = 1	-	-	-	-	-	-	REL	2F	rr	3
BIL rel	Branch if IRQ Pin Low	Branch if IRQ pin = 0	-	-	-	-	-	-	REL	2E	rr	3
BIT #opr8i BIT opr8a BIT opr16a BIT oprx16,X BIT oprx8,X BIT ,X BIT oprx16,SP BIT oprx8,SP	Bit Test	(A) & (M) (CCR Updated but Operands Not Changed)	0	_	_	\$	\$	_	IMM DIR EXT IX2 IX1 IX SP2 SP1	A5 B5 C5 D5 E5 F5 9ED5 9EE5	ii dd hh II ee ff ff ee ff ff	234 43354
BLE rel	Branch if Less Than or Equal To (Signed Operands)	Branch if (Z) (N \oplus V) = 1	-	-	-	-	-	-	REL	93	rr	3
BLO rel	Branch if Lower (Same as BCS)	Branch if (C) = 1	-	-	-	-	-	-	REL	25	rr	3
BLS <i>rel</i>	Branch if Lower or Same	Branch if $(C) \mid (Z) = 1$	-	-	-	-	-	-	REL	23	rr	3
BLT rel	Branch if Less Than (Signed Operands)	Branch if (N \oplus V) = 1	-	-	-	-	-	-	REL	91	rr	3
BMC rel	Branch if Interrupt Mask Clear	Branch if $(I) = 0$	-	-	-	-	-	-	REL	2C	rr	3
BMI rel	Branch if Minus	Branch if $(N) = 1$	-	-	-	-	-	-	REL	2B	rr	3
BMS rel	Branch if Interrupt Mask Set	Branch if (I) = 1	-	-	-	-	-	-	REL	2D	rr	3
BNE rel	Branch if Not Equal	Branch if $(Z) = 0$	-	-	-	-	-	-	REL	26	rr	3
BPL <i>rel</i>	Branch if Plus	Branch if (N) = 0	-	-	-	-	-	-	REL	2A	rr	3
BRA rel	Branch Always	No Test	-	-	-	-	-	-	REL	20	rr	3

Table 7-2. The Sub mistruction Set Summary (Sheet 2 of 7
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Source		_		c	Eff	iec CC	t R		ess	ode	and	rcles ¹
Form	Form Operation Description		v	н	I	N	z	с	Addr Moo	Opco	Opera	Bus Cy
CPX #opr8i CPX opr8a CPX opr16a CPX oprx16,X CPX oprx8,X CPX ,X CPX oprx16,SP CPX oprx8,SP	Compare X (Index Register Low) with Memory	(X) – (M) (CCR Updated But Operands Not Changed)	\$	_	_	\$	\$	\$	IMM DIR EXT IX2 IX1 IX SP2 SP1	A3 B3 C3 D3 E3 F3 9ED3 9EE3	ii dd hh II ee ff ff ee ff ff	2 3 4 3 3 5 4
DAA	Decimal Adjust Accumulator After ADD or ADC of BCD Values	(A) ₁₀	υ	-	-	\$	¢	\$	INH	72		1
DBNZ opr8a,rel DBNZA rel DBNZX rel DBNZ oprx8,X,rel DBNZ ,X,rel DBNZ oprx8,SP,rel	Decrement and Branch if Not Zero	Decrement A, X, or M Branch if (result) ≠ 0 DBNZX Affects X Not H	_	_	_	_	_	_	DIR INH INH IX1 IX SP1	3B 4B 5B 6B 7B 9E6B	dd rr rr ff rr ff rr ff rr	7 4 7 6 8
DEC opr8a DECA DECX DEC oprx8,X DEC ,X DEC oprx8,SP	Decrement	$\begin{array}{l} M \leftarrow (M) - 0x01 \\ A \leftarrow (A) - 0x01 \\ X \leftarrow (X) - 0x01 \\ M \leftarrow (M) - 0x01 \end{array}$	\$	_	_	¢	¢	_	DIR INH INH IX1 IX SP1	3A 4A 5A 6A 7A 9E6A	dd ff ff	5 1 5 4 6
DIV	Divide	$A \leftarrow (H:A) \div (X)$ H \leftarrow Remainder	-	-	-	_	\$	\$	INH	52		6
EOR #opr8i EOR opr8a EOR opr16a EOR oprx16,X EOR oprx8,X EOR ,X EOR oprx16,SP EOR oprx8,SP	Exclusive OR Memory with Accumulator	$A \gets (A \oplus M)$	0	_	_	\$	\$	_	IMM DIR EXT IX2 IX1 IX SP2 SP1	A8 B8 C8 D8 E8 F8 9ED8 9EE8	ii dd hh II ee ff ff ee ff	2 3 4 3 3 3 5 4
INC opr8a INCA INCX INC oprx8,X INC ,X INC oprx8,SP	Increment	$\begin{array}{l} M \gets (M) + 0x01 \\ A \gets (A) + 0x01 \\ X \gets (X) + 0x01 \\ M \gets (M) + 0x01 \end{array}$	\$	_	_	\$	\$	_	DIR INH INH IX1 IX SP1	3C 4C 5C 6C 7C 9E6C	dd ff ff	5 1 1 5 4 6
JMP opr8a JMP opr16a JMP oprx16,X JMP oprx8,X JMP ,X	Jump	$PC \gets Jump \; Address$	_	_	_	_	_	_	DIR EXT IX2 IX1 IX	BC CC DC EC FC	dd hh II ee ff ff	3 4 4 3 3
JSR opr8a JSR opr16a JSR oprx16,X JSR oprx8,X JSR ,X	Jump to Subroutine	$\begin{array}{l} PC \leftarrow (PC) + n \ (n = 1, 2, \text{ or } 3) \\ Push \ (PCL); \ SP \leftarrow (SP) - 0x0001 \\ Push \ (PCH); \ SP \leftarrow (SP) - 0x0001 \\ PC \leftarrow Unconditional \ Address \end{array}$	_	-	_	_	_	_	DIR EXT IX2 IX1 IX	BD CD DD ED FD	dd hh II ee ff ff	56655
LDA #opr8i LDA opr8a LDA opr16a LDA opr16,X LDA oprx8,X LDA oprx16,SP LDA oprx8,SP	Load Accumulator from Memory	A ← (M)	0	_	_	\$	\$	_	IMM DIR EXT IX2 IX1 IX SP2 SP1	A6 B6 C6 D6 E6 F6 9ED6 9EE6	ii dd hh II ee ff ff ee ff ff	2 3 4 3 3 5 4
LDHX #opr16i LDHX opr8a LDHX opr16a LDHX ,X LDHX oprx16,X LDHX oprx8,X LDHX oprx8,SP	Load Index Register (H:X) from Memory	H:X ← (M:M + 0x0001)	0	_	_	\$	\$	_	IMM DIR EXT IX IX2 IX1 SP1	45 55 32 9EAE 9EBE 9ECE 9EFE	jj kł dd hh II ee ff ff	3455655

Table 7-2. HCS08 Instruction Set Summary (Sheet 4 of 7)



Chapter 8 Internal Clock Generator (S08ICGV4)

8.4.7.1 FLL Engaged External Unlocked

FEE unlocked is entered when FEE is entered and the count error (Δn) output from the subtractor is greater than the maximum n_{unlock} or less than the minimum n_{unlock} , as required by the lock detector to detect the unlock condition.

The ICG will remain in this state while the count error (Δn) is greater than the maximum n_{lock} or less than the minimum n_{lock} , as required by the lock detector to detect the lock condition.

In this state, the pulse counter, subtractor, digital loop filter, and DCO form a closed loop and attempt to lock it according to their operational descriptions later in this section. Upon entering this state and until the FLL becomes locked, the output clock signal ICGOUT frequency is given by $f_{ICGDCLK} / (2 \times R)$ This extra divide by two prevents frequency overshoots during the initial locking process from exceeding chip-level maximum frequency specifications. After the FLL has locked, if an unexpected loss of lock causes it to re-enter the unlocked state while the ICG remains in FEE mode, the output clock signal ICGOUT frequency is given by $f_{ICGDCLK} / R$.

8.4.7.2 FLL Engaged External Locked

FEE locked is entered from FEE unlocked when the count error (Δn) is less than n_{lock} (max) and greater than n_{lock} (min) for a given number of samples, as required by the lock detector to detect the lock condition. The output clock signal ICGOUT frequency is given by $f_{ICGDCLK}/R$. In FLL engaged external locked, the filter value is updated only once every four comparison cycles. The update made is an average of the error measurements taken in the four previous comparisons.

8.4.8 FLL Lock and Loss-of-Lock Detection

To determine the FLL locked and loss-of-lock conditions, the pulse counter counts the pulses of the DCO for one comparison cycle (see Table 8-9 for explanation of a comparison cycle) and passes this number to the subtractor. The subtractor compares this value to the value in MFD and produces a count error, Δn . To achieve locked status, Δn must be between n_{lock} (min) and n_{lock} (max). After the FLL has locked, Δn must stay between n_{unlock} (min) and n_{unlock} (max) to remain locked. If Δn goes outside this range unexpectedly, the LOLS status bit is set and remains set until cleared by software or until the MCU is reset. LOLS is cleared by reading ICGS1 then writing 1 to ICGIF (LOLRE = 0), or by a loss-of-lock induced reset (LOLRE = 1), or by any MCU reset.

If the ICG enters the off state due to stop mode when ENBDM = OSCSTEN = 0, the FLL loses locked status (LOCK is cleared), but LOLS remains unchanged because this is not an unexpected loss-of-lock condition. Though it would be unusual, if ENBDM is cleared to 0 while the MCU is in stop, the ICG enters the off state. Because this is an unexpected stopping of clocks, LOLS will be set when the MCU wakes up from stop.

Expected loss of lock occurs when the MFD or CLKS bits are changed or in FEI mode only, when the TRIM bits are changed. In these cases, the LOCK bit will be cleared until the FLL regains lock, but the LOLS will not be set.



Chapter 9 Keyboard Interrupt (S08KBIV1)

9.4.2 KBI Pin Enable Register (KBI1PE)



Figure 9-4. KBI Pin Enable Register (KBI1PE)

Table 9-3. KBI1	PE Register Field	Descriptions
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Field	Description
7:0 KBIPE[7:0]	 Keyboard Pin Enable for KBI Port Bits — Each of these read/write bits selects whether the associated KBI port pin is enabled as a keyboard interrupt input or functions as a general-purpose I/O pin. 0 Bit n of KBI port is a general-purpose I/O pin not associated with the KBI 1 Bit n of KBI port enabled as a keyboard interrupt input

9.5 Functional Description

9.5.1 Pin Enables

The KBIPEn control bits in the KBI1PE register allow a user to enable (KBIPEn = 1) any combination of KBI-related port pins to be connected to the KBI module. Pins corresponding to 0s in KBI1PE are general-purpose I/O pins that are not associated with the KBI module.

9.5.2 Edge and Level Sensitivity

Synchronous logic is used to detect edges. Prior to detecting an edge, enabled keyboard inputs in a KBI module must be at the deasserted logic level.

A falling edge is detected when an enabled keyboard input signal is seen as a logic 1 (the deasserted level) during one bus cycle and then a logic 0 (the asserted level) during the next cycle.

A rising edge is detected when the input signal is seen as a logic 0 during one bus cycle and then a logic 1 during the next cycle.

The KBIMOD control bit can be set to reconfigure the detection logic so that it detects edges and levels. In KBIMOD = 1 mode, the KBF status flag becomes set when an edge is detected (when one or more enabled pins change from the deasserted to the asserted level while all other enabled pins remain at their deasserted levels), but the flag is continuously set (and cannot be cleared) as long as any enabled keyboard input pin remains at the asserted level. When the MCU enters stop3 mode, the synchronous edge-detection logic is bypassed (because clocks are stopped). In stop3 mode, KBI inputs act as asynchronous level-sensitive inputs so they can wake the MCU from stop3 mode.



11.1.1 Features

Features of SCI module include:

- Full-duplex, standard non-return-to-zero (NRZ) format
- Double-buffered transmitter and receiver with separate enables
- Programmable baud rates (13-bit modulo divider)
- Interrupt-driven or polled operation:
 - Transmit data register empty and transmission complete
 - Receive data register full
 - Receive overrun, parity error, framing error, and noise error
 - Idle receiver detect
- Hardware parity generation and checking
- Programmable 8-bit or 9-bit character length
- Receiver wakeup by idle-line or address-mark
- Optional 13-bit break character
- Selectable transmitter output polarity

11.1.2 Modes of Operation

See Section 11.3, "Functional Description," for a detailed description of SCI operation in the different modes.

- 8- and 9-bit data modes
- Stop modes SCI is halted during all stop modes
- Loop mode
- Single-wire mode

11.1.3 Block Diagram

Figure 11-2 shows the transmitter portion of the SCI.



Chapter 13 Inter-Integrated Circuit (S08IICV1)

13.1 Introduction

The MC9S08AW60 Series of microcontrollers has an inter-integrated circuit (IIC) module for communication with other integrated circuits. The two pins associated with this module, SCL and SDA, are open-drain outputs and are shared with port C pins 0 and 1, respectively.

ICR (hex)	SCL Divider	SDA Hold Value
00	20	7
01	22	7
02	24	8
03	26	8
04	28	9
05	30	9
06	34	10
07	40	10
08	28	7
09	32	7
0A	36	9
0B	40	9
0C	44	11
0D	48	11
0E	56	13
0F	68	13
10	48	9
11	56	9
12	64	13
13	72	13
14	80	17
15	88	17
16	104	21
17	128	21
18	80	9
19	96	9
1A	112	17
1B	128	17
1C	144	25
1D	160	25
1E	192	33
1F	240	33

Table 13-3	IIC	Divider	and	Hold	Values
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ICR (hex)	SCL Divider	SDA Hold Value
20	160	17
21	192	17
22	224	33
23	256	33
24	288	49
25	320	49
26	384	65
27	480	65
28	320	33
29	384	33
2A	448	65
2B	512	65
2C	576	97
2D	640	97
2E	768	129
2F	960	129
30	640	65
31	768	65
32	896	129
33	1024	129
34	1152	193
35	1280	193
36	1536	257
37	1920	257
38	1280	129
39	1536	129
ЗA	1792	257
3B	2048	257
3C	2304	385
3D	2560	385
ЗE	3072	513
3F	3840	513



ADICLK	Selected Clock Source		
00	Bus clock		
01	Bus clock divided by 2		
10	Alternate clock (ALTCLK)		
11	Asynchronous clock (ADACK)		

Table 14-8. Input Clock Select

14.4.8 Pin Control 1 Register (APCTL1)

The pin control registers are used to disable the I/O port control of MCU pins used as analog inputs. APCTL1 is used to control the pins associated with channels 0–7 of the ADC module.



Figure 14-11. Pin Control 1 Register (APCTL1)

Description			
 ADC Pin Control 7 — ADPC7 is used to control the pin associated with channel AD7. 0 AD7 pin I/O control enabled 1 AD7 pin I/O control disabled 			
 ADC Pin Control 6 — ADPC6 is used to control the pin associated with channel AD6. 0 AD6 pin I/O control enabled 1 AD6 pin I/O control disabled 			
 ADC Pin Control 5 — ADPC5 is used to control the pin associated with channel AD5. 0 AD5 pin I/O control enabled 1 AD5 pin I/O control disabled 			
 ADC Pin Control 4 — ADPC4 is used to control the pin associated with channel AD4. 0 AD4 pin I/O control enabled 1 AD4 pin I/O control disabled 			
 ADC Pin Control 3 — ADPC3 is used to control the pin associated with channel AD3. 0 AD3 pin I/O control enabled 1 AD3 pin I/O control disabled 			
 ADC Pin Control 2 — ADPC2 is used to control the pin associated with channel AD2. 0 AD2 pin I/O control enabled 1 AD2 pin I/O control disabled 			

Table 14-9. APCTL1 Register Field Descriptions



Field	Description
1 ADPC17	 ADC Pin Control 17 — ADPC17 is used to control the pin associated with channel AD17. 0 AD17 pin I/O control enabled 1 AD17 pin I/O control disabled
0 ADPC16	 ADC Pin Control 16 — ADPC16 is used to control the pin associated with channel AD16. 0 AD16 pin I/O control enabled 1 AD16 pin I/O control disabled

Table 14-11. APCTL3 Register Field Descriptions (continued)

14.5 Functional Description

The ADC module is disabled during reset or when the ADCH bits are all high. The module is idle when a conversion has completed and another conversion has not been initiated. When idle, the module is in its lowest power state.

The ADC can perform an analog-to-digital conversion on any of the software selectable channels. The selected channel voltage is converted by a successive approximation algorithm into an 11-bit digital result. In 8-bit mode, the selected channel voltage is converted by a successive approximation algorithm into a 9-bit digital result.

When the conversion is completed, the result is placed in the data registers (ADC1RH and ADC1RL).In 10-bit mode, the result is rounded to 10 bits and placed in ADC1RH and ADC1RL. In 8-bit mode, the result is rounded to 8 bits and placed in ADC1RL. The conversion complete flag (COCO) is then set and an interrupt is generated if the conversion complete interrupt has been enabled (AIEN = 1).

The ADC module has the capability of automatically comparing the result of a conversion with the contents of its compare registers. The compare function is enabled by setting the ACFE bit and operates in conjunction with any of the conversion modes and configurations.

14.5.1 Clock Select and Divide Control

One of four clock sources can be selected as the clock source for the ADC module. This clock source is then divided by a configurable value to generate the input clock to the converter (ADCK). The clock is selected from one of the following sources by means of the ADICLK bits.

- The bus clock, which is equal to the frequency at which software is executed. This is the default selection following reset.
- The bus clock divided by 2. For higher bus clock rates, this allows a maximum divide by 16 of the bus clock.
- ALTCLK, as defined for this MCU (See module section introduction).
- The asynchronous clock (ADACK) This clock is generated from a clock source within the ADC module. When selected as the clock source this clock remains active while the MCU is in wait or stop3 mode and allows conversions in these modes for lower noise operation.

Whichever clock is selected, its frequency must fall within the specified frequency range for ADCK. If the available clocks are too slow, the ADC will not perform according to specifications. If the available clocks



result of the conversion is transferred to ADC1RH and ADC1RL upon completion of the conversion algorithm.

If the bus frequency is less than the f_{ADCK} frequency, precise sample time for continuous conversions cannot be guaranteed when short sample is enabled (ADLSMP=0). If the bus frequency is less than 1/11th of the f_{ADCK} frequency, precise sample time for continuous conversions cannot be guaranteed when long sample is enabled (ADLSMP=1).

The maximum total conversion time for different conditions is summarized in Table 14-12.

Conversion Type	ADICLK	ADLSMP	Max Total Conversion Time
Single or first continuous 8-bit	0x, 10	0	20 ADCK cycles + 5 bus clock cycles
Single or first continuous 10-bit	0x, 10	0	23 ADCK cycles + 5 bus clock cycles
Single or first continuous 8-bit	0x, 10	1	40 ADCK cycles + 5 bus clock cycles
Single or first continuous 10-bit	0x, 10	1	43 ADCK cycles + 5 bus clock cycles
Single or first continuous 8-bit	11	0	5 μ s + 20 ADCK + 5 bus clock cycles
Single or first continuous 10-bit	11	0	5 μ s + 23 ADCK + 5 bus clock cycles
Single or first continuous 8-bit	11	1	5 μ s + 40 ADCK + 5 bus clock cycles
Single or first continuous 10-bit	11	1	5 μ s + 43 ADCK + 5 bus clock cycles
Subsequent continuous 8-bit; $f_{BUS} \ge f_{ADCK}$	xx	0	17 ADCK cycles
Subsequent continuous 10-bit; $f_{BUS} \ge f_{ADCK}$	ХХ	0	20 ADCK cycles
Subsequent continuous 8-bit; $f_{BUS} \ge f_{ADCK}/11$	XX	1	37 ADCK cycles
Subsequent continuous 10-bit; $f_{BUS} \ge f_{ADCK}/11$	XX	1	40 ADCK cycles

Table 14-12. Total Conversion Time vs. Control Conditions

The maximum total conversion time is determined by the clock source chosen and the divide ratio selected. The clock source is selectable by the ADICLK bits, and the divide ratio is specified by the ADIV bits. For example, in 10-bit mode, with the bus clock selected as the input clock source, the input clock divide-by-1 ratio selected, and a bus frequency of 8 MHz, then the conversion time for a single conversion is:

Conversion time = $\frac{23 \text{ ADCK cyc}}{8 \text{ MHz/1}} + \frac{5 \text{ bus cyc}}{8 \text{ MHz}} = 3.5 \,\mu\text{s}$

Number of bus cycles = $3.5 \ \mu s \ x \ 8 \ MHz = 28 \ cycles$

NOTE

The ADCK frequency must be between f_{ADCK} minimum and f_{ADCK} maximum to meet ADC specifications.

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14.5.5 Automatic Compare Function

The compare function can be configured to check for either an upper limit or lower limit. After the input is sampled and converted, the result is added to the two's complement of the compare value (ADC1CVH and ADC1CVL). When comparing to an upper limit (ACFGT = 1), if the result is greater-than or equal-to the compare value, COCO is set. When comparing to a lower limit (ACFGT = 0), if the result is less than the compare value, COCO is set. The value generated by the addition of the conversion result and the two's complement of the compare value is transferred to ADC1RH and ADC1RL.

Upon completion of a conversion while the compare function is enabled, if the compare condition is not true, COCO is not set and no data is transferred to the result registers. An ADC interrupt is generated upon the setting of COCO if the ADC interrupt is enabled (AIEN = 1).

NOTE

The compare function can be used to monitor the voltage on a channel while the MCU is in either wait or stop3 mode. The ADC interrupt will wake the MCU when the compare condition is met.

14.5.6 MCU Wait Mode Operation

The WAIT instruction puts the MCU in a lower power-consumption standby mode from which recovery is very fast because the clock sources remain active. If a conversion is in progress when the MCU enters wait mode, it continues until completion. Conversions can be initiated while the MCU is in wait mode by means of the hardware trigger or if continuous conversions are enabled.

The bus clock, bus clock divided by two, and ADACK are available as conversion clock sources while in wait mode. The use of ALTCLK as the conversion clock source in wait is dependent on the definition of ALTCLK for this MCU. Consult the module introduction for information on ALTCLK specific to this MCU.

A conversion complete event sets the COCO and generates an ADC interrupt to wake the MCU from wait mode if the ADC interrupt is enabled (AIEN = 1).

14.5.7 MCU Stop3 Mode Operation

The STOP instruction is used to put the MCU in a low power-consumption standby mode during which most or all clock sources on the MCU are disabled.

14.5.7.1 Stop3 Mode With ADACK Disabled

If the asynchronous clock, ADACK, is not selected as the conversion clock, executing a STOP instruction aborts the current conversion and places the ADC in its idle state. The contents of ADC1RH and ADC1RL are unaffected by stop3 mode. After exiting from stop3 mode, a software or hardware trigger is required to resume conversions.



A.12 FLASH Specifications

This section provides details about program/erase times and program-erase endurance for the FLASH memory.

Program and erase operations do not require any special power sources other than the normal V_{DD} supply. For more detailed information about program/erase operations, see Chapter 4, "Memory."

Num	С	Characteristic	Symbol	Min	Typ ¹	Max	Unit
1	Р	Supply voltage for program/erase	V _{prog/erase}	2.7		5.5	V
2	Р	Supply voltage for read operation	V _{Read}	2.7		5.5	V
3	Р	Internal FCLK frequency ²	f _{FCLK}	150		200	kHz
4	Р	Internal FCLK period (1/FCLK)	t _{Fcyc}	5 6.67		μs	
5	Р	Byte program time (random location) ³	t _{prog}	9 t _{Fc}		t _{Fcyc}	
6	С	Byte program time (burst mode) ³	t _{Burst}	4 t _{Fcyc}		t _{Fcyc}	
7	Р	Page erase time ³	t _{Page}	4000 t _{Fcyc}		t _{Fcyc}	
8	Р	Mass erase time ³	t _{Mass}	20,000 t _f		t _{Fcyc}	
9	с	Program/erase endurance ⁴ T_L to $T_H = -40^{\circ}C$ to + 125°C $T = 25^{\circ}C$		10,000 — — — — — — — — — — — — — — — — —		cycles	
10	С	Data retention ⁵	t _{D_ret}	o_ret 15 100 —		years	

Table A-16. FLASH Characteristics

¹ Typical values are based on characterization data at V_{DD} = 5.0 V, 25°C unless otherwise stated.

² The frequency of this clock is controlled by a software setting.

- ⁴ Typical endurance for FLASH was evaluated for this product family on the 9S12Dx64. For additional information on how Freescale Semiconductor defines typical endurance, please refer to Engineering Bulletin EB619/D, *Typical Endurance for Nonvolatile Memory.*
- ⁵ Typical data retention values are based on intrinsic capability of the technology measured at high temperature and de-rated to 25°C using the Arrhenius equation. For additional information on how Freescale Semiconductor defines typical data retention, please refer to Engineering Bulletin EB618/D, *Typical Data Retention for Nonvolatile Memory.*

³ These values are hardware state machine controlled. User code does not need to count cycles. This information supplied for calculating approximate time to program and erase.



Appendix B Ordering Information and Mechanical Drawings

B.2 Orderable Part Numbering System

B.2.1 Consumer and Industrial Orderable Part Numbering System



B.2.2 Automotive Orderable Part Numbering System



B.3 Mechanical Drawings

This following pages contain mechanical specifications for MC9S08AW60 Series package options. See Table B-3 for the document numbers that correspond to each package type.

Pin Count	Туре	Designator	Document No.
44	LQFP	FG	98ASS23225W
48	QFN	FD	98ARH99048A
64	LQFP	PU	98ASS23234W
64	QFP	FU	98ASB42844B

Table B-3. Package Information



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